MPPS[™] Miniature Package Power Solutions 20V NPN LOW SATURATION TRANSISTOR AND 40V, 1A SCHOTTKY DIODE COMBINATION DUAL

SUMMARY

NPN Transistor — V_{CEO} = 20V; R_{SAT} = 47m Ω ; I_C = 4.5A

Schottky Diode — $V_R = 40V$; $V_F = 500mV$ (@1A); $I_C=1A$

DESCRIPTION

Packaged in the new innovative 3mm x 2mm MLP this combination dual comprises an ultra low saturation NPN transistor and a 1A Schottky barrier diode. This excellent combination provides users with highly efficient performance in applications including DC-DC and charging circuits.

Users will also gain several other key benefits:

Performance capability equivalent to much larger packages

- Improved circuit efficiency & power levels
- PCB area and device placement savings
- Lower package height (0.9mm nom)

Reduced component count

FEATURES

- Extremely Low Saturation Voltage (150mV @1A)
- H_{FF} characterised up to 6A
- I_C = 4.5A Continuous Collector Current
- Extremely Low V_F, fast switching Schottky
- 3mm x 2mm MLP

APPLICATIONS

- DC DC Converters
- Mobile Phones
- Charging Circuits
- Motor control

ORDERING INFORMATION

DEVICE	REEL	TAPE WIDTH	QUANTITY PER REEL
ZX3CDBS1M832TA	7′′	8mm	3000
ZX3CDBS1M832TC	13′′	8mm	10000

DEVICE MARKING

BS1

ISSUE 3- OCTOBER 2007



3mm x 2mm Dual Die MLP



PINOUT





ABSOLUTE MAXIMUM RATINGS.

PARAMETER	SYMBOL	VALUE	UNIT
Transistor			
Collector-Base Voltage	V _{CBO}	40	V
Collector-Emitter Voltage	V _{CEO}	20	V
Emitter-Base Voltage	V _{EBO}	7.5	V
Peak Pulse Current	I _{CM}	12	А
Continuous Collector Current (a)(f)	Ι _C	4.5	А
Continuous Collector Current (b)(f)	Ι _C	5	А
Base Current	I _B	1000	mA
Power Dissipation at TA=25°C (a)(f) Linear Derating Factor	P _D	1.5 12	W mW/°C
Power Dissipation at TA=25°C (b)(f) Linear Derating Factor	P _D	2.45 19.6	W mW/°C
Power Dissipation at TA=25°C (c)(f) Linear Derating Factor	P _D	1 8	W mW/°C
Power Dissipation at TA=25°C (d)(f) Linear Derating Factor	P _D	1.13 9	W mW/°C
Power Dissipation at TA=25°C (d)(g) Linear Derating Factor	P _D	1.7 13.6	W mW/°C
Power Dissipation at TA=25°C (e)(g) Linear Derating Factor	P _D	3 24	W mW/°C
Storage Temperature Range	T _{stg}	-55 to +150	°C
Junction Temperature	Ti	150	°C

THERMAL RESISTANCE

PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)(f)	R _{θJA}	83	°C/W
Junction to Ambient (b)(f)	R _{θJA}	51	°C/W
Junction to Ambient (c)(f)	R _{θJA}	125	°C/W
Junction to Ambient (d)(f)	R _{θJA}	111	°C/W
Junction to Ambient (d)(g)	R _{θJA}	73.5	°C/W
Junction to Ambient (e)(g)	R _{θJA}	41.7	°C/W

Notes

(a) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(b) Measured at t<5 secs for a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.
(c) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with minimal lead connections only.
(d) For a dual device surface mounted on 10 sq cm single sided 1oz copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(e) For a dual device surface mounted on 85 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device. (f) For a dual device with one active die.

(g) For dual device with 2 active die running at equal power.

(h) Repetitive rating - pulse width limited by max junction temperature. Refer to Transient Thermal Impedance graph.

(i) The minimum copper dimensions required for mounting are no smaller than the exposed metal pads on the base of the device as shown in the package dimensions data. The thermal resistance for a dual device mounted on 1.5mm thick FR4 board using minimum copper 1 oz weight, 1mm wide tracks and one half of the device active is Rth = 250°C/W giving a power rating of Ptot = 500mW.





TRANSISTOR TYPICAL CHARACTERISTICS



ABSOLUTE MAXIMUM RATINGS.

PARAMETER	SYMBOL	VALUE	UNIT	
Schottky Diode				
Continuous Reverse Voltage	V _R	40	V	
Forward Voltage @ I _F =1000mA(typ)	V _F	425	mV	
Forward Current	I _F	1850	mA	
Average Peak Forward Current D=50%	I _{FAV}	3	А	
Non Repetitive Forward Current ts 100 μ s ts 10ms	I _{FSM}	12 7	A A	
Power Dissipation at TA=25°C (a)(f) Linear Derating Factor	P _D 1.2 12		W mW/°C	
Power Dissipation at TA=25°C (b)(f) Linear Derating Factor	P _D	P _D 2 20		
Power Dissipation at TA=25°C (c)(f) Linear Derating Factor	P _D	0.8 8	W mW/°C	
Power Dissipation at TA=25°C (d)(f) Linear Derating Factor	P _D	0.9 9	W mW/°C	
Power Dissipation at TA=25°C (d)(g) Linear Derating Factor	P _D	1.36 13.6	W mW/°C	
Power Dissipation at TA=25°C (e)(g) Linear Derating Factor	P _D	2.4 24	W mW/°C	
Storage Temperature Range	T _{stg}	-55 to +150	°C	
Junction Temperature	Ti	125	°C	

THERMAL RESISTANCE

PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)(f)	R _{θJA}	83	°C/W
Junction to Ambient (b)(f)	R _{θJA}	51	°C/W
Junction to Ambient (c)(f)	R _{θJA}	125	°C/W
Junction to Ambient (d)(f)	R _{θJA}	111	°C/W
Junction to Ambient (d)(g)	R _{θJA}	73.5	°C/W
Junction to Ambient (e)(g)	R _{θJA}	41.7	°C/W

Notes

(a) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(b) Measured at t<5 secs for a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.
 (c) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with minimal lead connections only.

(d) For a dual device surface mounted on 10 sq cm single sided 1oz copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(e) For a dual device surface mounted on 85 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.
 (f) For a dual device with one active die.

(g) For dual device with 2 active die running at equal power.

(h) Repetitive rating - pulse width limited by max junction temperature. Refer to Transient Thermal Impedance graph.

(i) The minimum copper dimensions required for mounting are no smaller than the exposed metal pads on the base of the device as shown in the package dimensions data. The thermal resistance for a dual device mounted on 1.5mm thick FR4 board using minimum copper 1 oz weight, 1mm wide tracks and one half of the device active is Rth = 250°C/W giving a power rating of Ptot = 400mW.





SCHOTTKY TYPICAL CHARACTERISTICS



ELECTRICAL CHARACTERISTICS (at T _a	amb = 25°C unless otherwise stated).
--	--------------------------------------

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS.
TRANSISTOR ELECTRICAL CHARA	CTERISTICS					-
Collector-Base Breakdown Voltage	V _{(BR)CBO}	40	100		V	I _C =100μA
Collector-Emitter Breakdown Voltage	V _{(BR)CEO}	20	27		V	I _C =10mA*
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	7.5	8.2		V	I _E =100μA
Collector Cut-Off Current	I _{CBO}			25	nA	V _{CB} =32V
Emitter Cut-Off Current	I _{EBO}			25	nA	V _{EB} =6V
Collector Emitter Cut-Off Current	I _{CES}			25	nA	V _{CES} =16V
Collector-Emitter Saturation Voltage	V _{CE(sat)}		8 90 115 190 210	15 150 135 250 270	mV mV mV mV mV	I _C =0.1A, I _B =10mA* I _C =1A, I _B =10mA* I _C =2A, I _B =50mA* I _C =3A, I _B =100mA* I _C =4.5A, I _B =125mA*
Base-Emitter Saturation Voltage	$V_{BE(sat)}$		0.98	-1.05	V	I _C =4.5A, I _B =125mA*
Base-Emitter Turn-On Voltage	V _{BE(on)}		0.88	-0.95	V	I _C =4.5A, V _{CE} =2V*
Static Forward Current Transfer Ratio	h _{FE}	200 300 200 100	400 450 360 180			
Transition Frequency	f _T	100	140		MHz	I _C =50mA, V _{CE} =10V f=100MHz
Output Capacitance	C _{obo}		23	30	pF	V _{CB} =10V, f=1MHz
Turn-On Time	t _(on)		170		ns	V _{CC} =10V, I _C =3A
Turn-Off Time	t _(off)		400		ns	I _{B1} =I _{B2} =10mA
SCHOTTKY DIODE ELECTRICAL CH	ARACTERIS	TICS	•	•		·
Reverse Breakdown Voltage	V _{(BR)R}	40	60		V	I _R =300μA
Forward Voltage	V _F		240 265 305 355 390 425 495 420	270 290 340 400 450 500 600	mV mV mV mV mV mV mV	$I_{F}=50mA^{*}$ $I_{F}=100mA^{*}$ $I_{F}=250mA^{*}$ $I_{F}=500mA^{*}$ $I_{F}=750mA^{*}$ $I_{F}=1000mA^{*}$ $I_{F}=1500mA^{*}$ $I_{F}=1000mA, T_{a}=100^{\circ}C^{*}$
Reverse Current	I _R		50	100	μΑ	V _R =30V
Diode Capacitance	C _D		25		pF	f=1MHz,V _R =25V
Reverse Recovery Time	t _{rr}		12		ns	switched from $I_F = 500$ mA to $I_R = 500$ m Measured at $I_R = 50$ mA

*Measured under pulsed conditions.





TRANSISTOR TYPICAL CHARACTERISTICS



SEMICONDUCTORS



SCHOTTKY TYPICAL CHARACTERISTICS



*Exposed Flags. Solder connection to improve thermal dissipation is optional. F1 at collector 1 potential

F2 at collector 2 potential

CONTROLLING DIMENSIONS IN MILLIMETRES APPROX. CONVERTED DIMENSIONS IN INCHES

MLP832 PACKAGE DIMENSIONS

	MILLIMETRES		INCHES			MILLIN	IETRES	INC	HES
DIM	MIN.	MAX.	MIN.	MAX.	DIM	MIN.	MAX.	MIN.	MAX.
А	0.80	1.00	0.031	0.039	е	0.65	REF	0.025	6 BSC
A1	0.00	0.05	0.00	0.002	E	2.00	BSC	0.0787	7 BSC
A2	0.65	0.75	0.0255	0.0295	E2	0.43	0.63	0.017	0.0249
A3	0.15	0.25	0.006	0.0098	E4	0.16	0.36	0.006	0.014
b	0.24	0.34	0.009	0.013	L	0.20	0.45	0.0078	0.0157
b1	0.17	0.30	0.0066	0.0118	L2		0.125	0.00	0.005
D	3.00	BSC	0.118 BSC		r	0.075	BSC	0.002	9 BSC
D2	0.82	1.02	0.032	0.040	θ	0°	12°	0°	12°
D3	1.01	1.21	0.0397	0.0476					

© Zetex Semiconductors plc 2004

Europe	Americas	Asia Pacific	Corporate Headquarters
Zetex GmbH	Zetex Inc	Zetex (Asia) Ltd	Zetex Semiconductors plc
Streitfeldstraße 19	700 Veterans Memorial Hwy	3701-04 Metroplaza Tower 1	Lansdowne Road, Chadderton
D-81673 München	Hauppauge, NY 11788	Hing Fong Road, Kwai Fong	Oldham, OL9 9TY
Germany	USA	Hong Kong	United Kingdom
Telefon: (49) 89 45 49 49 0	Telephone: (1) 631 360 2222	Telephone: (852) 26100 611	Telephone (44) 161 622 4444
Fax: (49) 89 45 49 49 49	Fax: (1) 631 360 8222	Fax: (852) 24250 494	Fax: (44) 161 622 4446
<u>europe.sales@zetex.com</u>	<u>usa.sales@zetex.com</u>	<u>asia.sales@zetex.com</u>	<u>hq@zetex.com</u>

These offices are supported by agents and distributors in major countries world-wide.

This publication is issued to provide outline information only which (unless agreed by the Company in writing) may not be used, applied or reproduced for any purpose or form part of any order or contract or be regarded as a representation relating to the products or services concerned. The Company reserves the right to alter without notice the specification, design, price or conditions of supply of any product or service.

For the latest product information, log on to www.zetex.com

